

2832

**N THE UNITED STATES PATENT AND TRADEMARK OFFICE**

Applicant: Tetsuya Kawamoto, et al.  
Serial No.: 09/543,653  
Filed: April 5, 2000  
For: TEMPERATURE SENSOR  
(as amended)  
Group Art Unit: 2832  
Examiner: K. Easthom  
Attorney Docket: MURT P093

**CERTIFICATE OF MAILING**

Date of Deposit: February 11, 2004

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**INFORMATION DISCLOSURE STATEMENT**  
**PURSUANT TO 37 C.F.R. §1.56 AND §§1.97-1.98**

Commissioner for Patents  
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Sir:

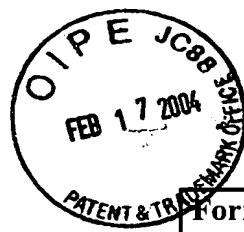
The following Form 1449 and a copies of documents listed thereon are being filed herewith as a Disclosure Statement. Consideration of the documents by the Patent Examiner, and the making them of record in the file of this application, are respectfully requested.

The information contained in this information disclosure statement was cited in a communication from a foreign patent office in a counterpart foreign application not more than three months prior to the filing of this statement.

Respectfully submitted,

  
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February 11, 2004  
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**Form 1449 (Modified)**
**Information Disclosure  
Statement By Applicant**

(Use Several Sheets if Necessary)

**Atty Docket No.**
**Application No.:**

MURT P093

09/543,653

**Applicant:**

Tetsuya Kawamoto, et al.

**Filing Date**
**Group**

April 5, 2000

2832

**U.S. Patent Documents**

Examiner Initial	No.	Patent No.	Date	Patentee	Class	Sub-class	Filing Date
A							
B							
C							
D							
E							
F							
G							
H							
I							

**Foreign Patent or Published Foreign Patent Application**

Examiner Initial	No.	Document No.	Publication Date	Country or Patent Office	Class	Sub-class	Translation	
							Yes	No
J	UM51-82945	07/02/76	JP					
K	UM5-79933	10/29/93	JP					
L	UM58-186483	12/10/83	JP					
M	UM59-68290	05/09/84	JP					
N								

**Other Documents**

Examiner Initial	No.	Author, Title, Date, Place (e.g. Journal) of Publication
O		
P		
Q		
Examiner		Date Considered

Examiner: Initial citation considered. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.